NC STATE UNIVERSITY

NEWS FROM THE ANALYTICAL INSTRUMENTATION FACILITY (AIF) - JULY 2018

AIF "Cool Science" Seminar

The "AIF Cool Science" seminar continues this summer on Friday, July 20 at 3:30 PM. This event includes Howling Cow ice cream, some time for networking and mingling, and an inspiring and fun science talk on time-resolved X-ray diffraction by Dr. Sem Gorfman from Tel Aviv University. Consider coming to cool off during the hot summer afternoon! Although the event is free, please register to attend in order to ensure we have plenty of cool ice cream for all. Location: Hunt Library, room 4106.

Learn More & RSVP »

AFM Workshop on Nanomechanics of Soft Materials (co-hosted by Asylum Research and AIF)

Discover how AFM can quantify nanomechanical properties in your research. In part 2 of our 3-part series, we'll discuss in-liquid imaging, force spectroscopy, and nanomechanics on soft materials. The technical presentation by Ryan Fuierer from Asylum Research is on Friday, July 27 from 10:00am-11:30am and the hands-on demonstrations from 12:30pm-3:30pm. Although the event is free, please register with Ryan Fuierer at ryan.fuierer@oxinst.com. Location: Monteith Research Center (MRC), room 463.

Learn More »

Confocal Laser Scanning Microscope for non-contact 3-D profilometry

We recently commissioned a new Keyence VKx1100, a Confocal Laser Scanning Microscope (CLSM). This microscope combines optical microscopy with laser profilometry, making it possible to obtain high resolution optical images to measure profiles and surface roughness. It can be used for almost any type of material. Questions? Contact Phillip Strader at pmstrade@ncsu.edu.

Learn More »

Bruker Hysitron TI 980 Triboindenter

We recently commissioned a new Bruker Hysitron TI980 Triboindenter, a quasistatic indentation system for nanomechanical testing of mechanical properties including Young's modulus, hardness, fracture toughness, nanoscratch, and wear. The TI980 is ideal for measuring mechanical properties of coatings and thin films, as well as the spatial dependence of properties. Its three-plate capacitive transducer design allows for a high displacement sensitivity and a low thermal drift. Questions? Contact Phillip Strader at pmstrade@ncsu.edu.

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Join our team! Postdoc opening in electron microscopy at AIF

The Analytical Instrumentation Facility (AIF) has an immediate opening for a postdoc in electron microscopy. The postdoc will provide training and expertise to our dynamic user base, collaborate with users, develop and publish new techniques, and deliver seminars and short courses. The postdoc will primarily work with the FEI Talos, FEI Titan, FEI Quanta, and FEI Verios instruments.

Apply Here »

Talos roll-out

The new FEI Talos transmission electron microscope, acquired under an MRI award to Professor Jim LeBeau (MSE), has arrived! We are targeting September 2018 for bringing users online. The instrument is located in room 1046A of EB-1.

Read our interview with Jim LeBeau »

FIB Short Course

AIF is offering another FIB short course on July 20th, 2018 which includes introductory lectures and hands-on demonstrations on the FEI Quanta Dual Beam FIB-FESEM. To ensure that each student receives maximum hands-on time, the course is limited to a small group of participants. For more details and to register, please contact Fred Stevie at fred_stevie@ncsu.edu.

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